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| INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) | | | | ATTY DOCKET NO. 18617 | | APPLICATION NO. 10/523418 | | |
| | | | | APPLICANT(S) Hiroo HONGO | | DTG Rec'd PCT/PTO 01 FEB 2005 | | |
| FILING DATE Herewith | | | | GROUP ART UNIT 2812 Unassigned | | | | |
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| *EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE | |
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| | | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION | |
| | | | | | | | YES | NO |
| /CL/ | | JP 2001-20072A | 1/23/2001 | Japan | | | | |
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| /CL/ | | H. Hongo, et al., Chemical Physics Letters (2002), "Chemical Vapor Deposition of Single-Wall Carbon Nanotubes on Iron-film-coated Sapphire Substrates" S.J. Wind, et al., Applied Physics Letters, Vol. 80, No. 20, (20 May 2002), "Vertical Scaling of Carbon Nanotube Field-Effect Transistors Using Top Gate Electrodes" | | | | | | |
| EXAMINER /Cheung Lee/ | | | | DATE CONSIDERED 10/25/2008 | | | | |

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

ATTY DOCKET NO.

18617

APPLICATION NO.

10523418

Hiroo HONGO

FILING

Herewith

DT05 Rec'd PCT/PTO 01 FEB 2005

GROUP ART

Unassigned 2812

U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

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| | | | | | | | YES | NO |
| /CL/ | | JP 2002-146534A | 5/22/2002 | Japan | | | | |
| /CL/ | | JP 2001-176431A | 6/29/2001 | Japan | | | | |
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/Cheung Lee/

DATE CONSIDERED

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| | | | | Hiroo HONGO DTOS Rec'd PCT/PTO | | 01 FEB 2005 | |
| FILING Herewith | | | | GROUP ART 2812 <i>Unassigned</i> | | | |

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| OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i> | | | |
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